# HD74LS249 .BCD-to-Seven-Segment Decoders/Drivers (with open collector outputs)

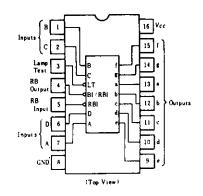
The HD74LS249 is 16-pin versions of the HD74LS49, respectively. Included in the HD74LS249 circuits is the full functional capability for lamp test and ripple blanking, which is not available in the HD74LS circuits. The HD74LS49 composes the  $\frac{L}{C_1}$  and  $\frac{L}{C_1}$  without tails and the HD74LS249 composes the  $\frac{L}{C_1}$  and  $\frac{L}{C_1}$  without tails and the HD74LS249 composes the  $\frac{L}{C_1}$  and  $\frac{L}{C_1}$  without tails. Composition of all other characters, including display patterns for BCD inputs above nine, is identical. The HD74LS249 features active-low outputs designed for driving indicators directly. All of the circuits have full ripple-blanking input/output controls and a lamp test input. Segment identification and resultant displays are shown below. Display patterns for BCD input counts above 9 are unique symbols to authenticate input conditions. This circuit incorporates automatic leading and/or trailing-edge zero-blanking control (RBI and RBO).

Lamp test (LT) of this type may be performed at any time when the BI/RBO node is at a high level. This type contains an overriding blanking input (BI) which can be used to control the lamp intensity be pulsing or to inhibit the outputs.

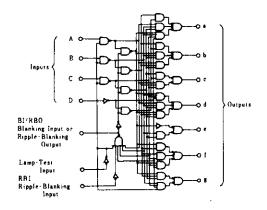
<b>ABSOLUTE</b>	MAXIMUM	RATINGS
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Item	Sym bol	Ratings	Unit
Supply voltage	Vcc	7.0	v
Input voltage	Vin	7.0	V
Output current (off-state)	IO(off)	1	mА
Operating temperature range	Topt	- 20 + 75	<b>°</b> C
Storage temperature range	Tris	$-65 \sim +150$	<b>°</b> C

#### PIN ARRANGEMENT



### 



## **#**RECOMMENDED OPERATING CONDITIONS

Item		Symbol	min	typ	max	Unit	
Output voltage	a∼g	Voн	-	_	5.5	v	
Output current	BI/RBO	Іон		-	- 50	μA	
	a~g	Iol	-	_	8		
	BI/RBO		-	_	3.2	- mA	

## FUNCTION TABLE

Decimal or			Inp	outs			BI/RBO				Outputs				Note
Function	LT	RBI	D	C	B	A	DI/ KDU	a	Ъ	c	d	e	f	g	Note
0	Н	н	L	L	L	L	н	H	н	H	Н	Н	H	L	
1	Н	×	L	L	L	H	Н	L	Н	H	L	L	[ L	L	I
2	Ĥ	×	L	L	н	Ĺ	Н	н	н	L	Н	H	L	H	
3	H	×	L	L	н	Н	H	Н	н	н	н	L	L	Н	]
4	Н	×	L	Н	L	L	Н	L	н	Н	L	L	H	Н	1
5	Н	×	L	Н	L	Н	Н	н	L	н	н	L	Ĥ	н	1
6	Ĥ	×	L	Н	н	Ĺ	Н	н	L	н	н	н	н	н	1
7	Н	×	L	н	Н	Н	Н	н	Н	Н	L	L	L	Ĺ	],
8	Н	×	н	L	L	Ĺ	Н	Н	н	н	H	H	н	Н	] '
9	Н	×	н	L	L	н	н	н	н	Н	н	L	Н	Н	]
10	н	×	Н	L	н	L	Н	L	L	L	н	н	L	Н	]
11	Н	×	Н	L	н	H	н	L	L	Н	Н	L	L	Н	]
12	Ĥ	×	Н	Н	L	L	н	L	н	L	L	L	Н	Н	]
13	Н	×	н	н	L	Н	н	Н	L	L	Н	L	Н	Н	]
14	Ĥ	×	Н	н	Ĥ	L	н	L	L	L	Ĥ	Н	Н	Н	]
15	н	×	Ĥ	Н	н	H	Н	L	L	[ L	L	L	L	L	]
BI	×	×	х	×	×	×	L	L	L	L	L	L	L	L	2
RBI	Н	L	L	L	L	L	L	L	L	L	L	L	L	] L	3
LT	L	×	×	×	×	×	Н	Н	Н	Н	Н	Н	H	H	4

H; high level, L; low level, X; irrelevant

- Notes: 1. The blanking input (BI) must be open or held at a high logic level when output functions 0 through 15 are desired.
  - 2. When a low logic level is applied directly to blanking input (B1), all segment outputs are low regardless of the level of any other input.
- 3. When ripple-blanking input (RBI) and inputs A B, C, and D are at a low level with the lamp-test input high, all segment outputs go low and the ripple-blanking output (RBO) goes to a low level (response condition).
- 4. When a blanking input/ripple blanking output (BI/RBO) is open or held high and a low is applied to the lamp-test input, all segment outputs are high.

## **ELECTRICAL CHARACTERISTICS** ( $Ta = -20 \sim +75^{\circ}C$ )

It	em	Symbol	Test Conditions		min	typ*	max	Unit
		VIH		•	2.0			v
Input voltage		VII.			_		0.8	v
Output voltage	BI/RBO	Voн	$V_{CC} = 4.75V, V_{IH} = 2V, V_{IL} = 0.8V,$	<i>Іон =</i> 50 µ А	2.4	-	—	v
Output current	a∼g	Іон	$V_{CC} = 4.75V, V_{IH} = 2V, V_{IL} = 0.8V,$	Voн=5.5V	-		250	μA
				<i>IoL</i> = 1.6mA	-		0.4	- v
	BI/RBO		$V_{CC} = 4.75V, V_{IH} = 2V, V_{IL} = 0.8V$	$I_{OL} = 3.2 \text{mA}$	-	-	0.5	
Output voltage a~		Vol	$V_{CC} = 4.75$ V, $V_{IH} = 2$ V, $V_{IL} = 0.8$ V	$I_{OL} = 4 \text{mA}$	_	61	0.4	
	a∼g			Io1 = 8mA	-	-	0.5	
	except BI/RBO	Іін	$V_{cc} = 5.25 V, V_l = 2.7 V$			-	20	μA
	except BI/RBO				-	-	- 0.4	
Input current	BI/RBO	ΠL	$V_{CC} = 5.25 \text{V},  V_I = 0.4 \text{V}$			-	·· 1.2	mA
	except BI/RBO	h	$V_{CC} = 5.25 V, V_{f} = 7 V$			-	0.1	mA
Short-circuit output current	BI/RBO	los	$V_{CC} = 5.25 V$		-0.3	_	- 2	mA
Supply current	**	Icc	$V_{CC} = 5.25 V$		-	8	15	mА
Input clamp vol		Vik	$V_{CC} = 4.75$ V, $I_{IN} = -18$ mA	1	-	-	-1.5	v

\* V<sub>CC</sub>=5V, Ta=25°C

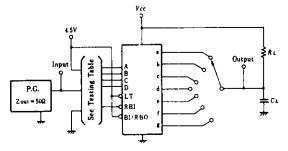
\*\*  $I_{CC}$  is measured with all outputs open and all inputs at 4.5V.

## **E**SWITCHING CHARACTERISTICS ( $V_{cc} = 5V$ , $T_a = 25^{\circ}C$ )

Item	Symbol	Input	Test Conditions	min	typ	max	Unit	
, <u>, , , , , , , , , , , , , , , , , , </u>	t₽LH		$C_L = 15 \mathrm{pF}$	-	_	100		
	<b>ℓ</b> PHL	A	$R_L = 2k \Omega$	_	. <del>.</del>	100	ns	
Propagation delay time	1PLH		$C_L = 15 \text{pF}$	-		100		
}	tPHL	RBI	$R_L = 6 k \Omega$		_	100	ns ns	

## **TESTING METHOD**

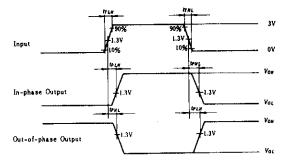
1) Test Circuit



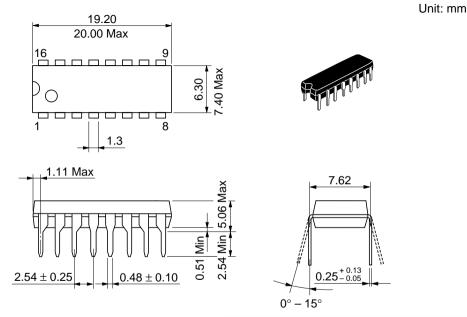
#### 2) Testing Table

Inputs					Outputs							
Item	RBI	D	С	B	A	a	Ь	с	d	e	f	g
	4.5V	GND	GND	GND	IN	OUT			TUO	OUT	OUT	
<b>t</b> PLH	4.5V	GND	GND	4.5V	IN	-	-	OUT	-	OUT	-	-
<b>I</b> PHL	4.5V	GND	4.5V	4.5V	IN	-	OUT	-	OUT	OUT	OUT	OU'
	IN	GND	GND	GND	GND	Ουτ	OUT	OUT	OUT	OUT	OUT	-

Waveform

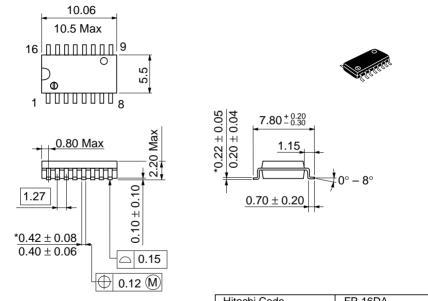


- Notes) 1. Input pulse:  $t_{TLH} \leq 15$  ns,  $t_{THL} \leq 6$  ns, PRR = 1 MHz, duty cycle=50%.
  - 2.  $C_L$  includes probe and jig capacitance.



Hitachi Code	DP-16
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	1.07 g

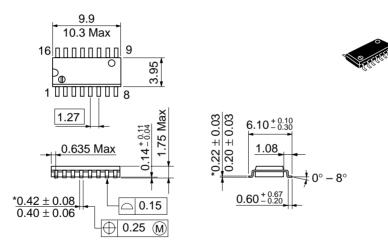
Unit: mm



\*Dimension including the plating thickness Base material dimension

Hitachi Code	FP-16DA
JEDEC	_
EIAJ	Conforms
Weight (reference value)	0.24 g

Unit: mm



\*Dimension including the plating thickness Base material dimension

Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

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